

CAV24C32

32-Kb I²C CMOS Serial EEPROM

Description

The CAV24C32 is a 32-Kb CMOS Serial EEPROM devices, internally organized as 4096 words of 8 bits each.

It features a 32-byte page write buffer and supports the Standard (100 kHz) and Fast (400 kHz) I²C protocol.

External address pins make it possible to address up to eight CAV24C32 devices on the same bus.

Features

- Automotive Temperature Grade 1 (−40°C to +125°C)
- Supports Standard and Fast I²C Protocol
- 2.5 V to 5.5 V Supply Voltage Range
- 32-Byte Page Write Buffer
- Hardware Write Protection for Entire Memory
- CAV Prefix for Automotive and Other Applications Requiring Site and Change Control
- Schmitt Triggers and Noise Suppression Filters on I²C Bus Inputs (SCL and SDA)
- Low Power CMOS Technology
- 1,000,000 Program/Erase Cycles
- 100 Year Data Retention
- SOIC, TSSOP 8-lead, and WLCSP 4-Ball and 5-Ball Packages
- This Device is Pb-Free, Halogen Free/BFR Free, and RoHS Compliant

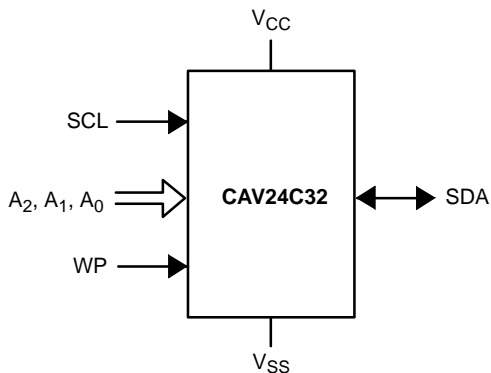


Figure 1. Functional Symbol



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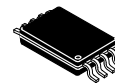
WLCSP5
C5A SUFFIX
CASE 567JQ



WLCSP4
C4C SUFFIX
CASE 567JY

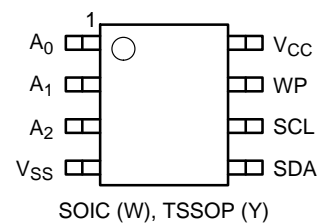
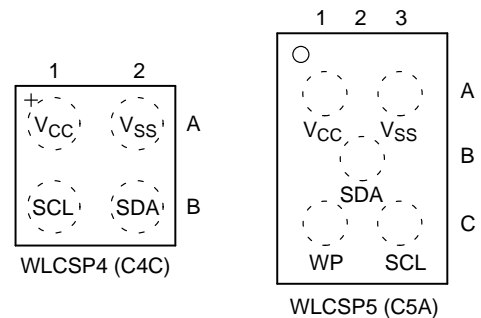


SOIC-8
W SUFFIX
CASE 751BD



TSSOP-8
Y SUFFIX
CASE 948AL

PIN CONFIGURATIONS (Top Views)



For the location of Pin 1, please consult the corresponding package drawing.

PIN FUNCTION

| Pin Name | Function |
|-----------------|--------------------------|
| A0, A1, A2 | Device Address Input |
| SDA | Serial Data Input/Output |
| SCL | Serial Clock Input |
| WP | Write Protect Input |
| V _{CC} | Power Supply |
| V _{SS} | Ground |

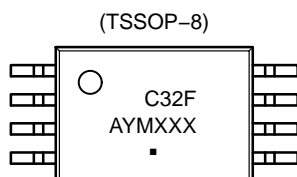
ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 12 of this data sheet.

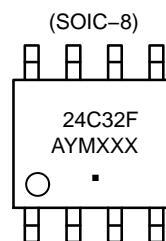
This document contains information on some products that are still under development. ON Semiconductor reserves the right to change or discontinue these products without notice.

CAV24C32

DEVICE MARKINGS



C32F = Specific Device Code
 A = Assembly Location
 Y = Production Year (Last Digit)
 M = Production Month (1-9, O, N, D)
 XXX = Last Three Digits of Assembly Lot Number
 ■ = Pb-Free Package



24C32F = Specific Device Code
 A = Assembly Location
 Y = Production Year (Last Digit)
 M = Production Month (1-9, O, N, D)
 XXX = Last Three Digits of Assembly Lot Number
 ■ = Pb-Free Package

(WLCSP-5)



2 = Specific Device Code
 Y = Production Year (Last Digit)
 M = Production Month (1-9, O, N, D)

(WLCSP-4)



B = Specific Device Code
 Y = Production Year (Last Digit)
 M = Production Month (1-9, O, N, D)

Table 1. ABSOLUTE MAXIMUM RATINGS

| Parameters | Ratings | Units |
|--|--------------|-------|
| Storage Temperature | -65 to +150 | °C |
| Voltage on any Pin with Respect to Ground (Note 1) | -0.5 to +6.5 | V |

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- During input transitions, voltage undershoot on any pin should not exceed -1 V for more than 20 ns. Voltage overshoot on pins A₀, A₁, A₂ and WP should not exceed V_{CC} + 1 V for more than 20 ns, while voltage on the I²C bus pins, SCL and SDA, should not exceed the absolute maximum ratings, irrespective of V_{CC}.

Table 2. RELIABILITY CHARACTERISTICS (Note 2)

| Symbol | Parameter | Min | Units |
|---------------------------|----------------|-----------|----------------------|
| N _{END} (Note 3) | Endurance | 1,000,000 | Program/Erase Cycles |
| T _{DR} | Data Retention | 100 | Years |

- These parameters are tested initially and after a design or process change that affects the parameter according to appropriate AEC-Q100 and JEDEC test methods.
- Page Mode, V_{CC} = 5 V, 25°C.

Table 3. D.C. OPERATING CHARACTERISTICS (V_{CC} = 2.5 V to 5.5 V, T_A = -40°C to +125°C, unless otherwise specified.)

| Symbol | Parameter | Test Conditions | | Min | Max | Units |
|------------------|--------------------|---|----------------------------------|-----------------------|-----------------------|-------|
| I _{CCR} | Read Current | Read, f _{SCL} = 400 kHz | | | 1 | mA |
| I _{CCW} | Write Current | Write, f _{SCL} = 400 kHz | | | 2 | mA |
| I _{SB} | Standby Current | All I/O Pins at GND or V _{CC} | T _A = -40°C to +125°C | | 5 | μA |
| I _L | I/O Pin Leakage | Pin at GND or V _{CC} | | | 2 | μA |
| V _{IL} | Input Low Voltage | | | -0.5 | 0.3 x V _{CC} | V |
| V _{IH} | Input High Voltage | A ₀ , A ₁ , A ₂ and WP | | 0.7 x V _{CC} | V _{CC} + 0.5 | V |
| | | SCL and SDA | | 0.7 x V _{CC} | 5.5 | |
| V _{OL} | Output Low Voltage | V _{CC} > 2.5 V, I _{OL} = 3 mA | | | 0.4 | V |

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

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Table 4. PIN IMPEDANCE CHARACTERISTICS ($V_{CC} = 2.5\text{ V to }5.5\text{ V}$, $T_A = -40^\circ\text{C to }+125^\circ\text{C}$, unless otherwise specified.)

| Symbol | Parameter | Conditions | Max | Units |
|-------------------|--|--|-----|---------------|
| C_{IN} (Note 4) | SDA I/O Pin Capacitance | $V_{IN} = 0\text{ V}$, $T_A = 25^\circ\text{C}$, $V_{CC} = 5.0\text{ V}$ | 8 | pF |
| C_{IN} (Note 4) | Input Capacitance (other pins) | $V_{IN} = 0\text{ V}$, $T_A = 25^\circ\text{C}$, $V_{CC} = 5.0\text{ V}$ | 6 | pF |
| I_{WP} (Note 5) | WP Input Current | $V_{IN} < V_{IH}$, $V_{CC} = 5.5\text{ V}$ | 130 | μA |
| | | $V_{IN} < V_{IH}$, $V_{CC} = 3.3\text{ V}$ | 120 | |
| | | $V_{IN} < V_{IH}$, $V_{CC} = 2.5\text{ V}$ | 80 | |
| | | $V_{IN} < V_{IH}$ | 2 | |
| I_A (Note 5) | Address Input Current (A0, A1, A2) Product Rev F | $V_{IN} < V_{IH}$, $V_{CC} = 5.5\text{ V}$ | 50 | μA |
| | | $V_{IN} < V_{IH}$, $V_{CC} = 3.3\text{ V}$ | 35 | |
| | | $V_{IN} < V_{IH}$, $V_{CC} = 2.5\text{ V}$ | 25 | |
| | | $V_{IN} > V_{IH}$ | 2 | |

- These parameters are tested initially and after a design or process change that affects the parameter according to appropriate AEC-Q100 and JEDEC test methods.
- When not driven, the WP, A0, A1 and A2 pins are pulled down to GND internally. For improved noise immunity, the internal pull-down is relatively strong; therefore the external driver must be able to supply the pull-down current when attempting to drive the input HIGH. To conserve power, as the input level exceeds the trip point of the CMOS input buffer ($\sim 0.5 \times V_{CC}$), the strong pull-down reverts to a weak current source.

Table 5. A.C. CHARACTERISTICS ($V_{CC} = 2.5\text{ V to }5.5\text{ V}$, $T_A = -40^\circ\text{C to }+125^\circ\text{C}$, unless otherwise specified.) (Note 6)

| Symbol | Parameter | Standard | | Fast | | Units |
|-----------------------|--|----------|------|------|-----|---------------|
| | | Min | Max | Min | Max | |
| F_{SCL} | Clock Frequency | | 100 | | 400 | kHz |
| $t_{HD:STA}$ | START Condition Hold Time | 4 | | 0.6 | | μs |
| t_{LOW} | Low Period of SCL Clock | 4.7 | | 1.3 | | μs |
| t_{HIGH} | High Period of SCL Clock | 4 | | 0.6 | | μs |
| $t_{SU:STA}$ | START Condition Setup Time | 4.7 | | 0.6 | | μs |
| $t_{HD:DAT}$ | Data In Hold Time | 0 | | 0 | | μs |
| $t_{SU:DAT}$ | Data In Setup Time | 250 | | 100 | | ns |
| t_R | SDA and SCL Rise Time | | 1000 | | 300 | ns |
| t_F (Note 6) | SDA and SCL Fall Time | | 300 | | 300 | ns |
| $t_{SU:STO}$ | STOP Condition Setup Time | 4 | | 0.6 | | μs |
| t_{BUF} | Bus Free Time Between STOP and START | 4.7 | | 1.3 | | μs |
| t_{AA} | SCL Low to Data Out Valid | | 3.5 | | 0.9 | μs |
| t_{DH} | Data Out Hold Time | 100 | | 100 | | ns |
| T_i (Note 6) | Noise Pulse Filtered at SCL and SDA Inputs | | 100 | | 100 | ns |
| $t_{SU:WP}$ | WP Setup Time | 0 | | 0 | | μs |
| $t_{HD:WP}$ | WP Hold Time | 2.5 | | 2.5 | | μs |
| t_{WR} | Write Cycle Time | | 5 | | 5 | ms |
| t_{PU} (Notes 7, 8) | Power-up to Ready Mode | | 1 | | 1 | ms |

- Test conditions according to "AC Test Conditions" table.
- Tested initially and after a design or process change that affects this parameter.
- t_{PU} is the delay between the time V_{CC} is stable and the device is ready to accept commands.

Table 6. A.C. TEST CONDITIONS

| | |
|--------------------------|---|
| Input Drive Levels | $0.2 \times V_{CC}$ to $0.8 \times V_{CC}$ |
| Input Rise and Fall Time | $\leq 50\text{ ns}$ |
| Input Reference Levels | $0.3 \times V_{CC}$, $0.7 \times V_{CC}$ |
| Output Reference Level | $0.5 \times V_{CC}$ |
| Output Test Load | Current Source $I_{OL} = 3\text{ mA}$; $C_L = 100\text{ pF}$ |

Power-On Reset (POR)

Each CAV24C32 incorporates Power-On Reset (POR) circuitry which protects the internal logic against powering up in the wrong state. The device will power up into Standby mode after V_{CC} exceeds the POR trigger level and will power down into Reset mode when V_{CC} drops below the POR trigger level. This bi-directional POR behavior protects the device against ‘brown-out’ failure following a temporary loss of power.

Pin Description

SCL: The Serial Clock input pin accepts the clock signal generated by the Master.

SDA: The Serial Data I/O pin accepts input data and delivers output data. In transmit mode, this pin is open drain. Data is acquired on the positive edge, and is delivered on the negative edge of SCL.

A₀, A₁ and A₂: The Address inputs set the device address that must be matched by the corresponding Slave address bits. The Address inputs are hard-wired HIGH or LOW allowing for up to eight devices to be used (cascaded) on the same bus. When left floating, these pins are pulled LOW internally.

WP: When pulled HIGH, the Write Protect input pin inhibits all write operations. When left floating, this pin is pulled LOW internally.

Functional Description

The CAV24C32 supports the Inter-Integrated Circuit (I²C) Bus protocol. The protocol relies on the use of a Master device, which provides the clock and directs bus traffic, and Slave devices which execute requests. The CAV24C32 operates as a Slave device. Both Master and Slave can transmit or receive, but only the Master can assign those roles.

I²C Bus Protocol

The 2-wire I²C bus consists of two lines, SCL and SDA, connected to the V_{CC} supply via pull-up resistors. The Master provides the clock to the SCL line, and either the Master or the Slaves drive the SDA line. A ‘0’ is transmitted by pulling a line LOW and a ‘1’ by letting it stay HIGH. Data transfer may be initiated only when the bus is not busy (see A.C. Characteristics). During data transfer, SDA must remain stable while SCL is HIGH.

START/STOP Condition

An SDA transition while SCL is HIGH creates a START or STOP condition (Figure 2). The START consists of a HIGH to LOW SDA transition, while SCL is HIGH. Absent the START, a Slave will not respond to the Master. The STOP completes all commands, and consists of a LOW to HIGH SDA transition, while SCL is HIGH.

Device Addressing

The Master addresses a Slave by creating a START condition and then broadcasting an 8-bit Slave address. For the CAV24C32, the first four bits of the Slave address are set to 1010 (Ah); the next three bits, A₂, A₁ and A₀, must match the logic state of the similarly named input pins. The R/W bit tells the Slave whether the Master intends to read (1) or write (0) data (Figure 3).

Acknowledge

During the 9th clock cycle following every byte sent to the bus, the transmitter releases the SDA line, allowing the receiver to respond. The receiver then either acknowledges (ACK) by pulling SDA LOW, or does not acknowledge (NoACK) by letting SDA stay HIGH (Figure 4). Bus timing is illustrated in Figure 5.

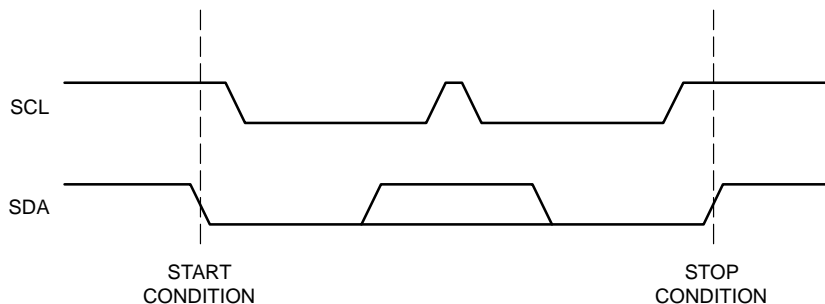


Figure 2. Start/Stop Timing

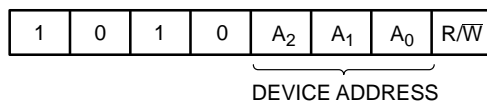


Figure 3. Slave Address Bits

CAV24C32

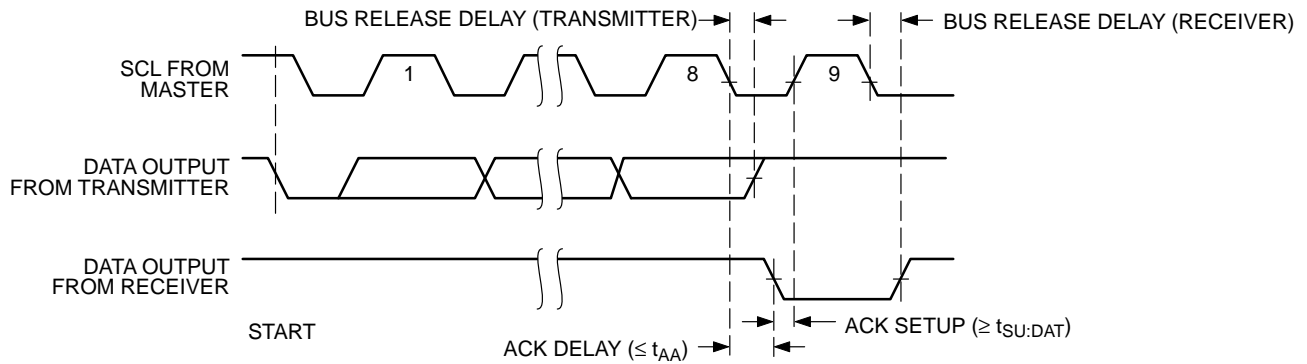


Figure 4. Acknowledge Timing

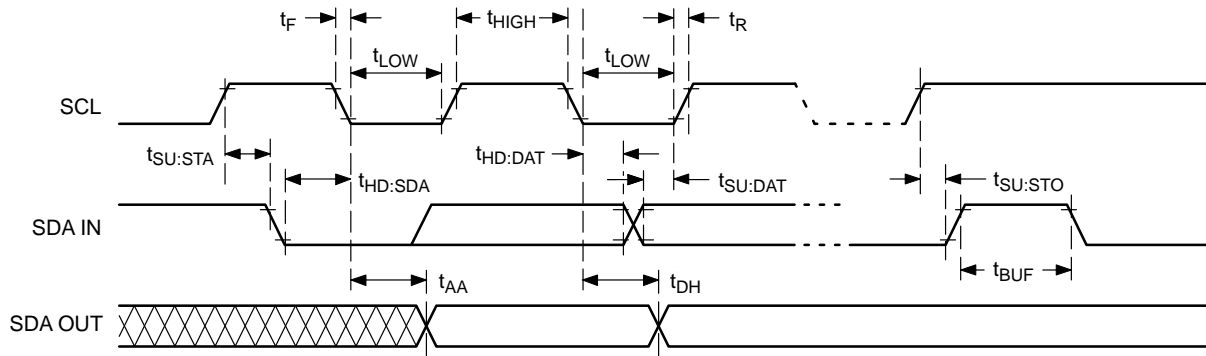


Figure 5. Bus Timing

WRITE OPERATIONS

Byte Write

To write data to memory, the Master creates a START condition on the bus and then broadcasts a Slave address with the R/\overline{W} bit set to '0'. The Master then sends two address bytes and a data byte and concludes the session by creating a STOP condition on the bus. The Slave responds with ACK after every byte sent by the Master (Figure 6). The STOP starts the internal Write cycle, and while this operation is in progress (t_{WR}), the SDA output is tri-stated and the Slave does not acknowledge the Master (Figure 7).

Page Write

The Byte Write operation can be expanded to Page Write, by sending more than one data byte to the Slave before issuing the STOP condition (Figure 8). Up to 32 distinct data bytes can be loaded into the internal Page Write Buffer starting at the address provided by the Master. The page address is latched, and as long as the Master keeps sending data, the internal byte address is incremented up to the end of page, where it then wraps around (within the page). New data can therefore replace data loaded earlier. Following the STOP, data loaded during the Page Write session will be written to memory in a single internal Write cycle (t_{WR}).

Acknowledge Polling

As soon (and as long) as internal Write is in progress, the Slave will not acknowledge the Master. This feature enables the Master to immediately follow-up with a new Read or Write request, rather than wait for the maximum specified Write time (t_{WR}) to elapse. Upon receiving a NoACK response from the Slave, the Master simply repeats the request until the Slave responds with ACK.

Hardware Write Protection

With the WP pin held HIGH, the entire memory is protected against Write operations. If the WP pin is left floating or is grounded, it has no impact on the Write operation. The state of the WP pin is strobed on the last falling edge of SCL immediately preceding the 1st data byte (Figure 9). If the WP pin is HIGH during the strobe interval, the Slave will not acknowledge the data byte and the Write request will be rejected.

Delivery State

The CAV24C32 is shipped erased, i.e., all bytes are FFh.

CAV24C32

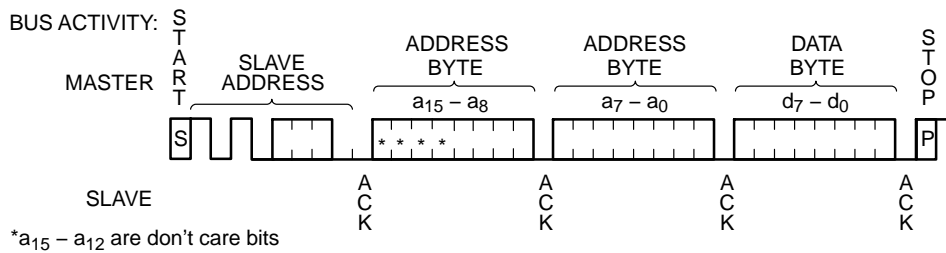


Figure 6. Byte Write Sequence

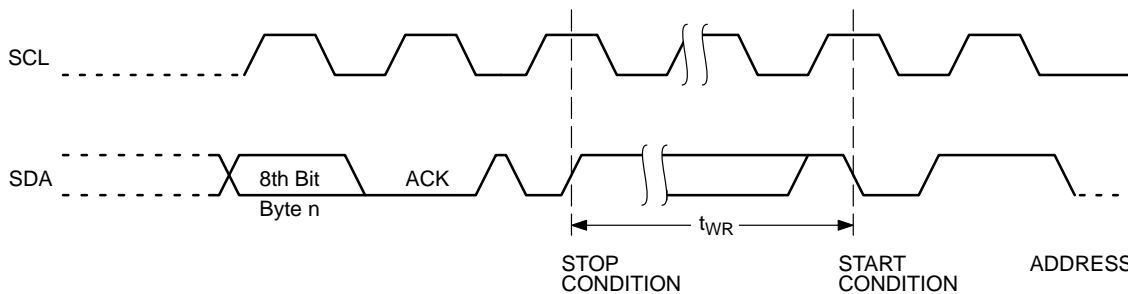


Figure 7. Write Cycle Timing

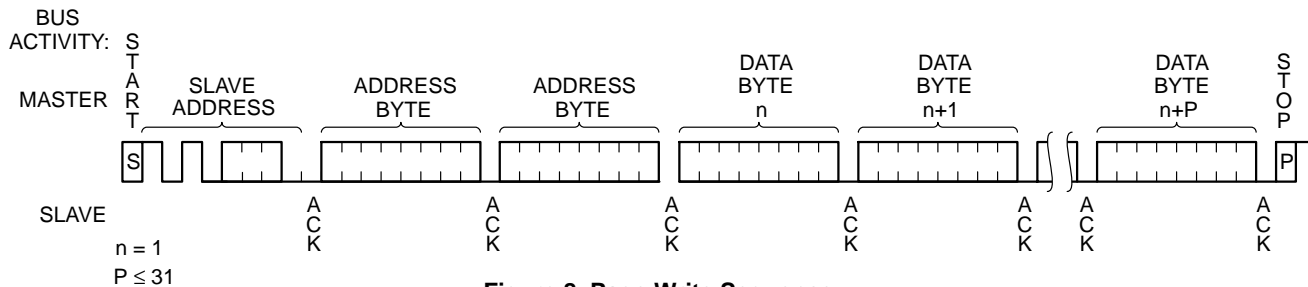


Figure 8. Page Write Sequence

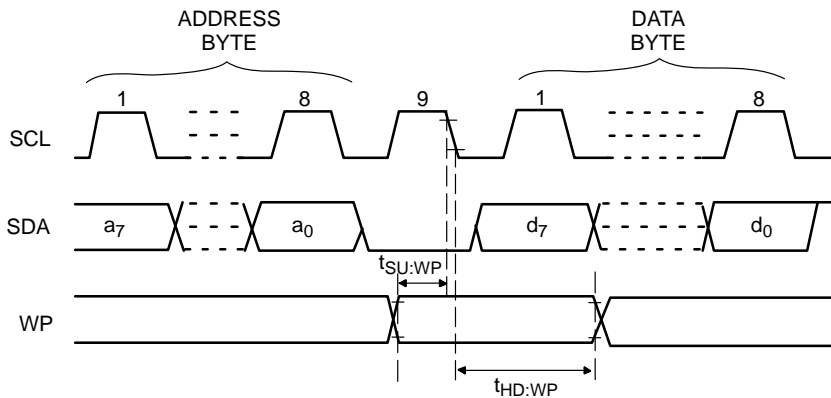


Figure 9. WP Timing

READ OPERATIONS

Immediate Read

To read data from memory, the Master creates a START condition on the bus and then broadcasts a Slave address with the R/\overline{W} bit set to '1'. The Slave responds with ACK and starts shifting out data residing at the current address. After receiving the data, the Master responds with NoACK and terminates the session by creating a STOP condition on the bus (Figure 10). The Slave then returns to Standby mode.

Selective Read

To read data residing at a specific address, the selected address must first be loaded into the internal address register. This is done by starting a Byte Write sequence, whereby the Master creates a START condition, then broadcasts a Slave address with the R/\overline{W} bit set to '0' and then sends two address bytes to the Slave. Rather than completing the Byte

Write sequence by sending data, the Master then creates a START condition and broadcasts a Slave address with the R/\overline{W} bit set to '1'. The Slave responds with ACK after every byte sent by the Master and then sends out data residing at the selected address. After receiving the data, the Master responds with NoACK and then terminates the session by creating a STOP condition on the bus (Figure 11).

Sequential Read

If, after receiving data sent by the Slave, the Master responds with ACK, then the Slave will continue transmitting until the Master responds with NoACK followed by STOP (Figure 12). During Sequential Read the internal byte address is automatically incremented up to the end of memory, where it then wraps around to the beginning of memory.

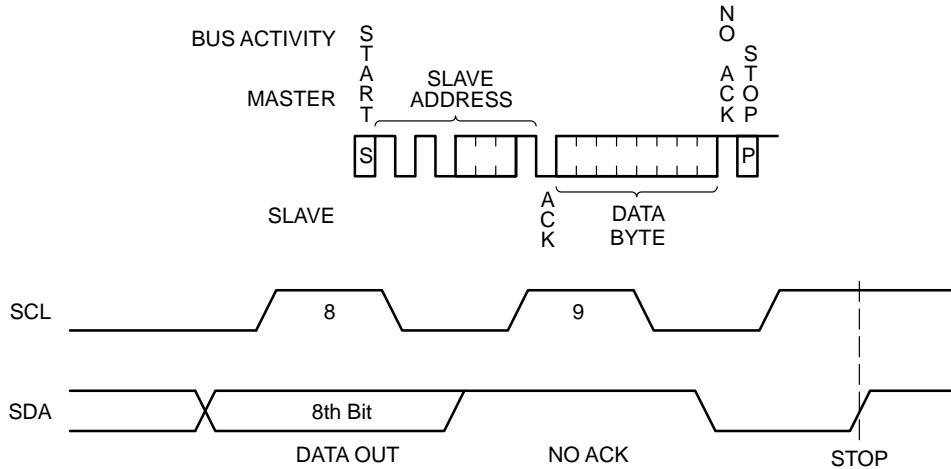


Figure 10. Immediate Read Sequence and Timing

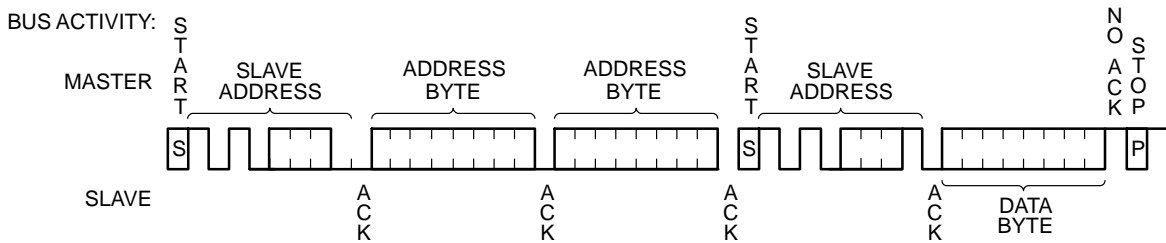


Figure 11. Selective Read Sequence

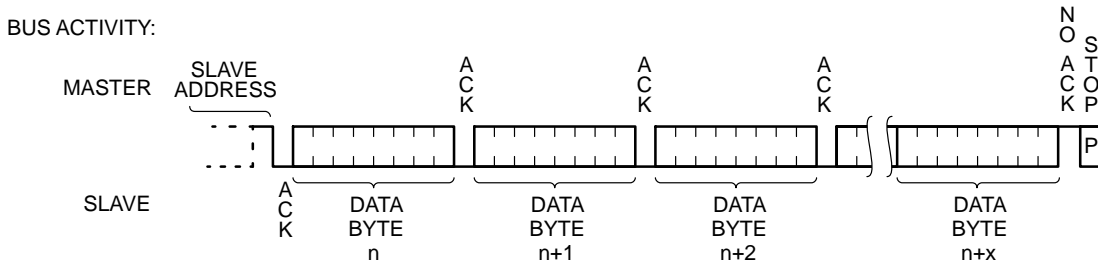
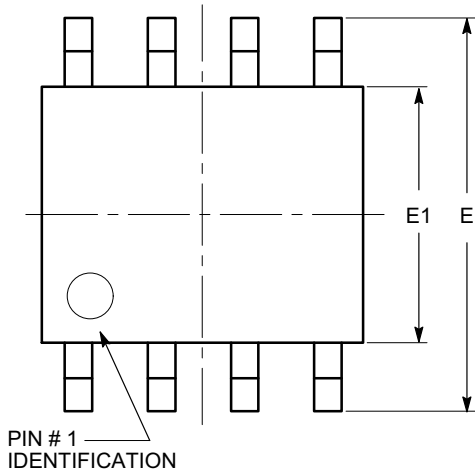


Figure 12. Sequential Read Sequence

CAV24C32

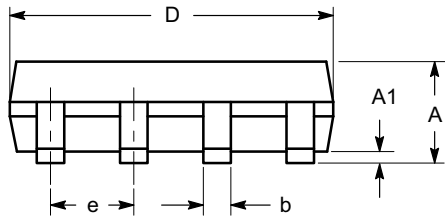
PACKAGE DIMENSIONS

SOIC 8, 150 mils
CASE 751BD
ISSUE O

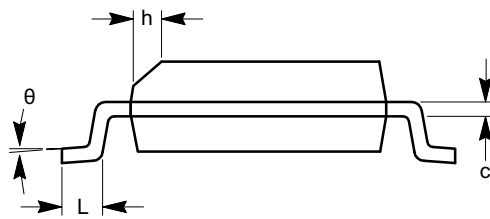


TOP VIEW

| SYMBOL | MIN | NOM | MAX |
|----------|----------|-----|------|
| A | 1.35 | | 1.75 |
| A1 | 0.10 | | 0.25 |
| b | 0.33 | | 0.51 |
| c | 0.19 | | 0.25 |
| D | 4.80 | | 5.00 |
| E | 5.80 | | 6.20 |
| E1 | 3.80 | | 4.00 |
| e | 1.27 BSC | | |
| h | 0.25 | | 0.50 |
| L | 0.40 | | 1.27 |
| θ | 0° | | 8° |



SIDE VIEW



END VIEW

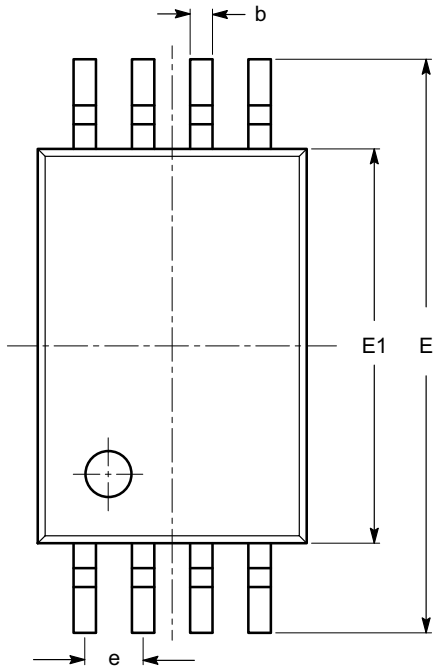
Notes:

- (1) All dimensions are in millimeters. Angles in degrees.
- (2) Complies with JEDEC MS-012.

CAV24C32

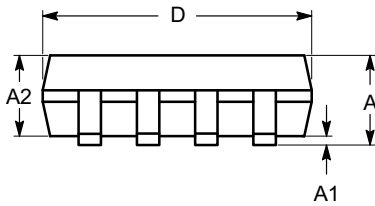
PACKAGE DIMENSIONS

TSSOP8, 4.4x3
CASE 948AL
ISSUE O

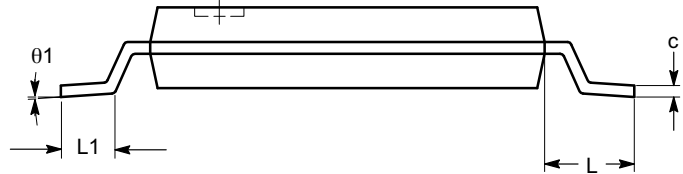


| SYMBOL | MIN | NOM | MAX |
|----------|----------|------|------|
| A | | | 1.20 |
| A1 | 0.05 | | 0.15 |
| A2 | 0.80 | 0.90 | 1.05 |
| b | 0.19 | | 0.30 |
| c | 0.09 | | 0.20 |
| D | 2.90 | 3.00 | 3.10 |
| E | 6.30 | 6.40 | 6.50 |
| E1 | 4.30 | 4.40 | 4.50 |
| e | 0.65 BSC | | |
| L | 1.00 REF | | |
| L1 | 0.50 | 0.60 | 0.75 |
| θ | 0° | | 8° |

TOP VIEW



SIDE VIEW



END VIEW

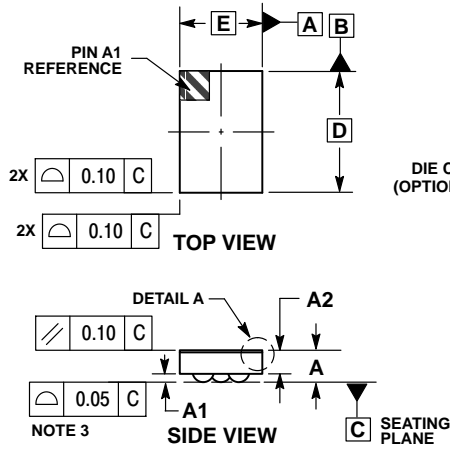
Notes:

- (1) All dimensions are in millimeters. Angles in degrees.
- (2) Complies with JEDEC MO-153.

CAV24C32

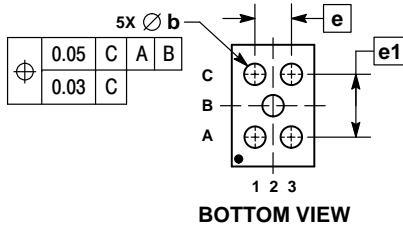
PACKAGE DIMENSIONS

WLCSP5, 1.34x0.91
CASE 567JQ
ISSUE A

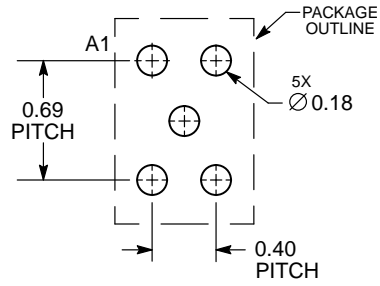


- NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
 2. CONTROLLING DIMENSION: MILLIMETERS.
 3. COPLANARITY APPLIES TO THE SPHERICAL CROWNS OF THE SOLDER BALLS.
 4. DIMENSION b IS MEASURED AT THE MAXIMUM BALL DIAMETER PARALLEL TO DATUM C.

| DIM | MILLIMETERS | |
|-----|-------------|------|
| | MIN | MAX |
| A | --- | 0.35 |
| A1 | 0.08 | 0.12 |
| A2 | 0.23 | REF |
| A3 | 0.025 | REF |
| b | 0.16 | 0.20 |
| D | 1.34 | BSC |
| E | 0.91 | BSC |
| e | 0.40 | BSC |
| e1 | 0.693 | BSC |



RECOMMENDED SOLDERING FOOTPRINT*



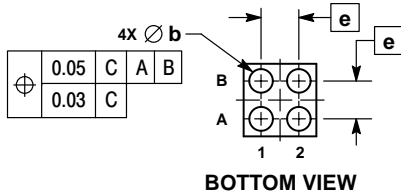
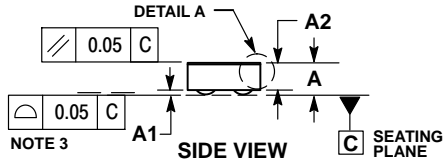
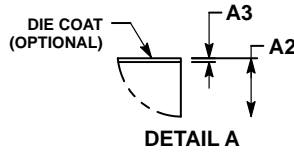
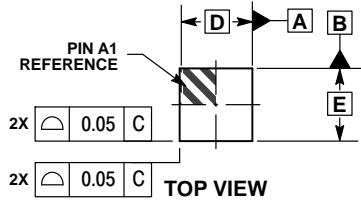
DIMENSIONS: MILLIMETERS

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

CAV24C32

PACKAGE DIMENSIONS

WLCSP4, 0.76x0.76
CASE 567JY
ISSUE O

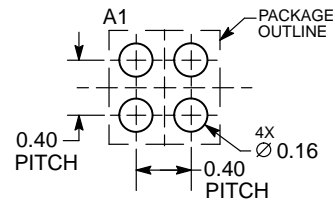


NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: MILLIMETERS.
3. COPLANARITY APPLIES TO SPHERICAL CROWNS OF SOLDER BALLS.

| DIM | MILLIMETERS | |
|-----|-------------|--------|
| | MIN | MAX |
| A | --- | 0.35 |
| A1 | 0.0415 | 0.0715 |
| A2 | 0.255 REF | |
| A3 | 0.025 REF | |
| b | 0.15 | 0.16 |
| D | 0.76 BSC | |
| E | 0.76 BSC | |
| e | 0.40 BSC | |

RECOMMENDED SOLDERING FOOTPRINT*



DIMENSIONS: MILLIMETERS

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CAV24C32

ORDERING INFORMATION

| Device Order Number | Specific Device Marking | Package Type | Lead Finish | Shipping |
|----------------------------|-------------------------|----------------------|-------------|---------------------------------|
| CAV24C32C5ATR (Note 10) | 2 | WLCSP5 | SnAgCu | Tape & Reel, 5,000 Units / Reel |
| CAV24C32C5CTR (Note 10) | P | WLCSP5 with Die Coat | SnAgCu | Tape & Reel, 5,000 Units / Reel |
| CAV24C32C4CTR (Note 10) | B | WLCSP4 with Die Coat | SnAgCu | Tape & Reel, 5,000 Units / Reel |
| CAV24C32WE-GT3 | 24C32F | SOIC-8, JEDEC | NiPdAu | Tape & Reel, 3,000 Units / Reel |
| CAV24C32YE-G (Note 10) | C32F | TSSOP-8 | NiPdAu | Tube, 100 Units / Tube |
| CAV24C32YE-GT3 | C32F | TSSOP-8 | NiPdAu | Tape & Reel, 3,000 Units / Reel |

9. All packages are RoHS-compliant (Lead-free, Halogen-free).
10. Please contact your nearest ON Semiconductor Sales office for availability.
11. For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.
12. **Caution: The EEPROM devices delivered in WLCSP must never be exposed to ultraviolet light. When exposed to ultraviolet light the EEPROM cells lose their stored data.**

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